Search Notes			

Application/Control No. Applicant(s)/Patent und Reexamination		er
10/552,487	YAMAKAWA ET AL.	
Examiner	Art Unit	
Patricia T. Nguyen	2817	

SEARCHED						
Cla	ss	Subclass	Date		Examiner	
33	0	289	2/3/2008		PN	
		295				
		296				
45	5	127.1				

INTERFERENCE SEARCHED						
Cla	ss	Subclass	Date		Examiner	
33	80	289	2/3/2008		PN	
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	455/	127.1				

SEARCH NOT	TES STRATEGY)
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